

PD - 95821 IRL8113 IRL8113S IRL8113L HEXFET® Power MOSFET

Applications

 High Frequency Synchronous Buck Converters for Computer Processor Power

V _{DSS}	R _{DS(on)} max	Qg (Typ.)
301/	6.0m()	23nC

Benefits

- Low R_{DS(on)} at 4.5V V_{GS}
- Low Gate Charge
- Fully Characterized Avalanche Voltage and Current

Ter .	TEST	Rep.
TO-220AB	D ² Pak	TO-262
IRL8113	IRL8113S	IRL8113L

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	105 ©	А
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	74 ⑥	
I _{DM}	Pulsed Drain Current ①	420	
P _D @T _C = 25°C	Maximum Power Dissipation	110	W
$P_D @ T_C = 100^{\circ}C$	Maximum Power Dissipation	57	
	Linear Derating Factor	0.76	W/°C
T _J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
·	Mounting Torque, 6-32 or M3 screw @	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ⑦		1.32	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface @	0.50		
$R_{\theta JA}$	Junction-to-Ambient ⊕⑦		62	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) © ⑦		40	

Notes ① through ⑦ are on page 12

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta \mathrm{BV}_{\mathrm{DSS}}/\Delta \mathrm{T}_{\mathrm{J}}$	Breakdown Voltage Temp. Coefficient		0.020	_	V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		4.8	6.0	mΩ	V _{GS} = 10V, I _D = 21A ③
			5.7	7.1		$V_{GS} = 4.5V, I_D = 17A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	1.35		2.25	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient		-5.0	_	mV/°C	
I _{DSS}	Drain-to-Source Leakage Current		_	1.0	μΑ	$V_{DS} = 24V, V_{GS} = 0V$
			_	150		$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I_{GSS}	Gate-to-Source Forward Leakage		_	100	nΑ	V _{GS} = 20V
	Gate-to-Source Reverse Leakage		_	-100		$V_{GS} = -20V$
gfs	Forward Transconductance	86	_		S	$V_{DS} = 15V, I_{D} = 17A$
Q_g	Total Gate Charge		23	35		
Q_{gs1}	Pre-Vth Gate-to-Source Charge	_	6.0	_		$V_{DS} = 15V$
Q_{gs2}	Post-Vth Gate-to-Source Charge		2.0		nC	$V_{GS} = 4.5V$
Q_{gd}	Gate-to-Drain Charge		8.3			I _D = 17A
Q_{godr}	Gate Charge Overdrive		6.7			See Fig. 16
Q_{sw}	Switch Charge (Q _{gs2} + Q _{gd})		10			
Q _{oss}	Output Charge		14		nC	$V_{DS} = 16V, V_{GS} = 0V$
t _{d(on)}	Turn-On Delay Time		14			$V_{DD} = 15V, V_{GS} = 4.5V$ ③
t _r	Rise Time		38			I _D = 17A
t _{d(off)}	Turn-Off Delay Time		18	_	ns	Clamped Inductive Load
t _f	Fall Time		5.0			
C _{iss}	Input Capacitance		2840			$V_{GS} = 0V$
C _{oss}	Output Capacitance		620		pF	V _{DS} = 15V
C _{rss}	Reverse Transfer Capacitance		290]	f = 1.0MHz

Avalanche Characteristics

	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy®		220	mJ
I _{AR}	Avalanche Current ①		17	Α
E_{AR}	Repetitive Avalanche Energy ①		11	mJ

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	105 ⑥		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			420		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage		_	1.0	V	$T_J = 25$ °C, $I_S = 17A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		18	27	ns	$T_J = 25$ °C, $I_F = 17A$, $V_{DD} = 15V$
Q_{rr}	Reverse Recovery Charge		7.2	11	nC	di/dt = 100A/µs ③

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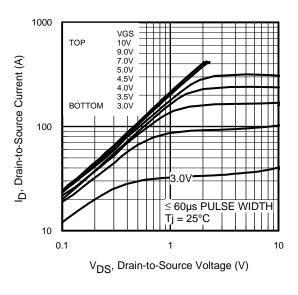


Fig 1. Typical Output Characteristics

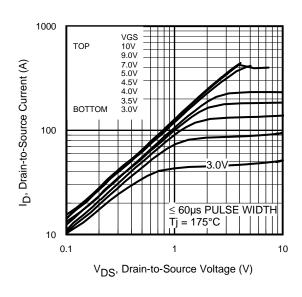


Fig 2. Typical Output Characteristics

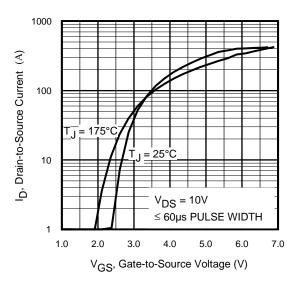


Fig 3. Typical Transfer Characteristics

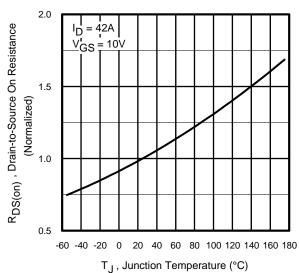


Fig 4. Normalized On-Resistance vs. Temperature

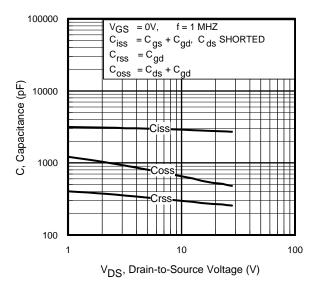


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

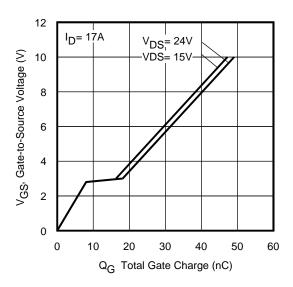


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

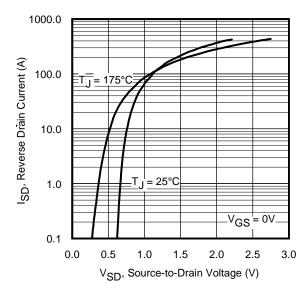


Fig 7. Typical Source-Drain Diode Forward Voltage

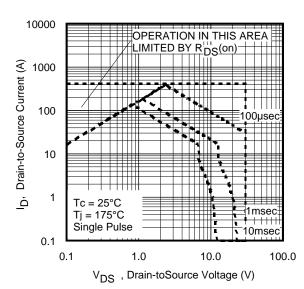
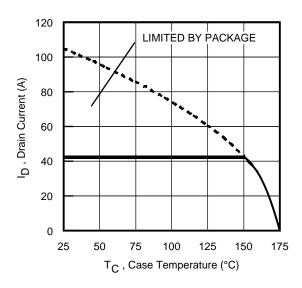


Fig 8. Maximum Safe Operating Area



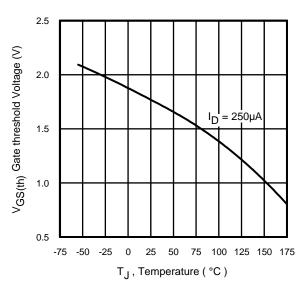


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Threshold Voltage vs. Temperature

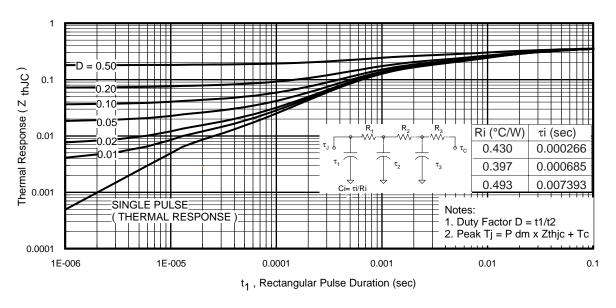


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

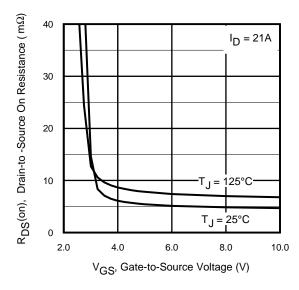


Fig 12. On-Resistance Vs. Gate Voltage

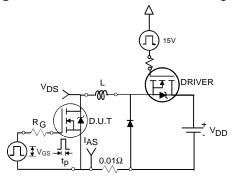


Fig 13a. Unclamped Inductive Test Circuit

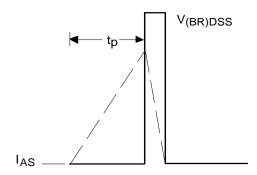


Fig 13b. Unclamped Inductive Waveforms

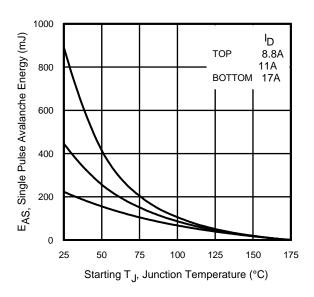


Fig 13c. Maximum Avalanche Energy Vs. Drain Current

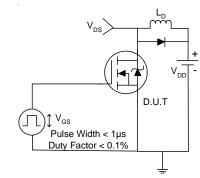


Fig 14a. Switching Time Test Circuit

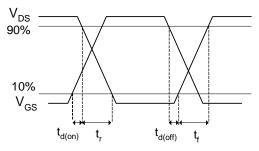


Fig 14b. Switching Time Waveforms www.irf.com

IRL8113/S/L

ld

Vgs

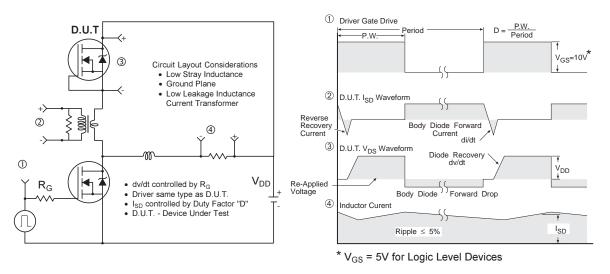


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

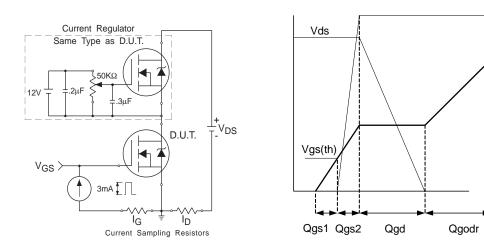


Fig 16. Gate Charge Test Circuit

Fig 17. Gate Charge Waveform

Power MOSFET Selection for Non-Isolated DC/DC Converters

Control FET

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the $R_{\rm ds(on)}$ of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms Q_{gs2} and Q_{oss} which are new to Power MOSFET data sheets.

 Q_{gs2} is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements, Q_{gs1} and Q_{gs2} , can be seen from Fig 16.

 Q_{gs2} indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to I_{dmax} at which time the drain voltage begins to change. Minimizing Q_{gs2} is a critical factor in reducing switching losses in Q1.

 $\rm Q_{\rm oss}$ is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how $\rm Q_{\rm oss}$ is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's $\rm C_{\rm ds}$ and $\rm C_{\rm dg}$ when multiplied by the power supply input buss voltage.

Synchronous FET

The power loss equation for Q2 is approximated by:

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

*dissipated primarily in Q1.

For the synchronous MOSFET Q2, $R_{\text{ds(on)}}$ is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge Q_{oss} and reverse recovery charge Q_{rr} both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and $V_{\rm in}$. As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of $Q_{\rm gd}/Q_{\rm gs1}$ must be minimized to reduce the potential for Cdv/dt turn on.

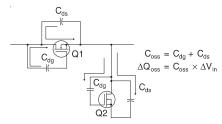
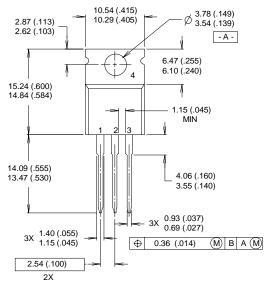


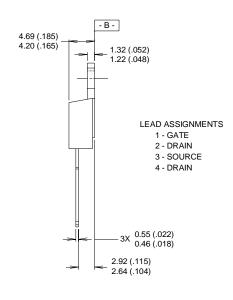
Figure A: Qoss Characteristic



TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 2 CONTROLLING DIMENSION: INCH

- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

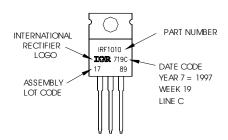
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997

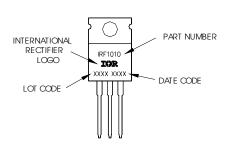
IN THE ASSEMBLY LINE "C"



For GB Production

EXAMPLE: THIS IS AN IRF1010 LOT CODE 1789

ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

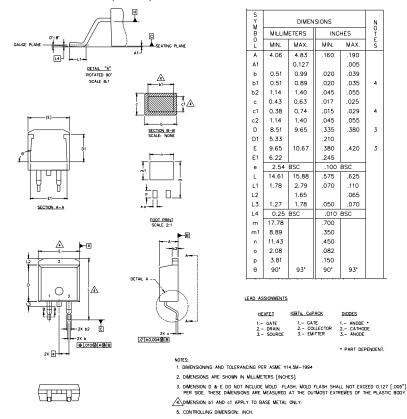


IRL8113/S/L

International IOR Rectifier

D²Pak Package Outline

Dimensions are shown in millimeters (inches)



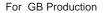
D²Pak Part Marking Information

EXAMPLE: THIS IS AN IRF530S WITH

LOT CODE 8024

ASSEMBLED ON WW 02, 2000

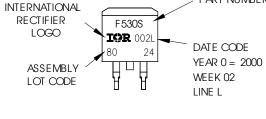
IN THE ASSEMBLY LINE "L"



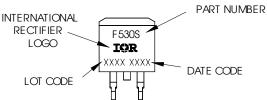
EXAMPLE: THIS IS AN IRF530S WITH

LOT CODE 8024

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PART NUMBER



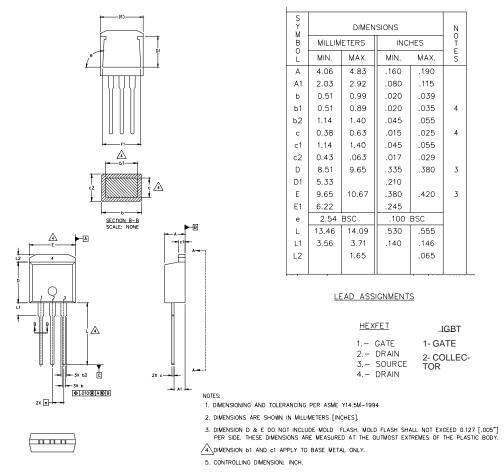
International

TOR Rectifier

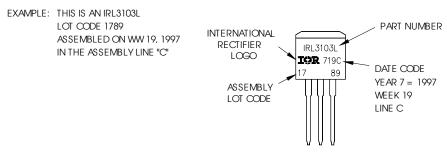
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TO-262 Package Outline

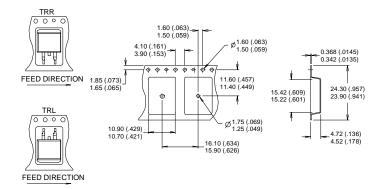
Dimensions are shown in millimeters (inches)

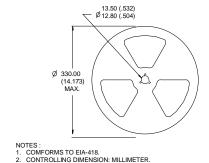


TO-262 Part Marking Information

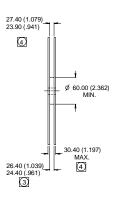


D²Pak Tape & Reel Information





DIMENSION MEASURED @ HUB. INCLUDES FLANGE DISTORTION @ OUTER EDGE.



- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^{\circ}C$, L = 1.58mH, $R_G = 25\Omega$, $I_{AS} = 21A$.
- 3 Pulse width \leq 400 μ s; duty cycle \leq 2%.
- 4 This is only applied to TO-220AB pakcage.
- ⑤ This is applied to D2Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- © Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 42A.
- ⑦ R_θ is measured at T_J approximately 90°C

TO-220AB package is not recommended for Surface Mount Application.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903

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